Express Mailing Label No.: EV247365945US

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Patent Application of:

Luca PUSTERLA et al.

Conf. No.: Not Yet Assigned Group Art Unit:

Not Yet Assigned

Appln. No.:

Not Yet Assigned

Examiner:

Not Yet Assigned

Filing Date:

Herewith

Attorney Docket No.:

6023-169US (BX2453M)

Title: METHOD FOR MEASURING THE

CONCENTRATION OF IMPURITIES

IN HELIUM BY ION MOBILITY

SPECTROMETRY

PRELIMINARY AMENDMENT

Simultaneously with the filing of the above-identified application with which this Preliminary Amendment is being filed, and prior to the calculation of the filing fee, Applicant hereby amends the application as follows, without prejudice:

Specification and Claim Amendments

Please amend the specification and claims as follows:

Please replace the specification and claims with the Substitute Specification and claims attached hereto. A marked-up copy of the specification and claims is also attached showing underlined additions and stricken deletions.